### GeneSiC SEMICONDUCTOR

### GA50JT12-247

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=

1200 V

1.4 V

50 A

28 mΩ

# Normally – OFF Silicon Carbide Junction Transistor

### Features

- 175 °C maximum operating temperature
- Temperature independent switching performance
- Gate oxide free SiC switch
- Suitable for connecting an anti-parallel diode
- Positive temperature coefficient for easy paralleling
- Low gate charge
- · Low intrinsic capacitance

## Package RoHS Compliant



 $V_{\text{DS}}$ 

ID

V<sub>DS(ON)</sub>

R<sub>DS(ON)</sub>

### Advantages

- · Low switching losses
- Higher efficiency
- High temperature operation
- · High short circuit withstand capability

#### **Applications**

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

### Maximum Ratings unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
Drain – Source Voltage	V <sub>DS</sub>	$V_{GS} = 0 V$	1200	V
Continuous Drain Current	I <sub>D</sub>	T <sub>C,MAX</sub> = 95 °C	50	А
Gate Peak Current	I <sub>GM</sub>		10	А
Turn-Off Safe Operating Area	RBSOA	$T_{VJ}$ = 175 °C, I <sub>G</sub> = 1 A, Clamped Inductive Load	I <sub>D,max</sub> = 50 @ V <sub>DS</sub> ≤ V <sub>DSmax</sub>	А
Short Circuit Safe Operating Area	SCSOA	$T_{VJ}$ = 175 °C, $I_G$ = 1 A, $V_{DS}$ = 800 V, Non Repetitive	20	μs
Reverse Gate – Source Voltage	V <sub>SG</sub>	·	30	V
Reverse Drain – Source Voltage	V <sub>SD</sub>		25	V
Power Dissipation	P <sub>tot</sub>	T <sub>c</sub> = 95 °C	308	W
Storage Temperature	T <sub>stg</sub>		-55 to 175	°C

### Electrical Characteristics at T<sub>j</sub> = 175 °C, unless otherwise specified

Devementer	Symbol	Conditions -	Values		Unit		
Parameter	Symbol	Conditions	min.	typ.	max.	Unit	
On Characteristics							
		$I_D$ = 50 A, $I_G$ = 1000 mA, $T_j$ = 25 °C		1.4			
Drain – Source On Voltage	V <sub>DS(ON)</sub>	$I_D$ = 50 A, $I_G$ = 2000 mA, $T_j$ = 125 °C		1.6		V	
		$I_D$ = 50 A, $I_G$ = 4000 mA, $T_j$ = 175 °C		2.2			
		I <sub>D</sub> = 50 A, I <sub>G</sub> = 1000 mA, T <sub>j</sub> = 25 °C		28			
Drain – Source On Resistance	R <sub>DS(ON)</sub>	I <sub>D</sub> = 50 A, I <sub>G</sub> = 2000 mA, T <sub>j</sub> = 125 °C		32		mΩ	
	· · ·	$I_D = 50 \text{ A}, I_G = 4000 \text{ mA}, T_j = 175 \text{ °C}$		44			
Cata Fanward Valtaga	N/	I <sub>G</sub> = 500 mA, T <sub>j</sub> = 25 °C		3.3		V	
Gate Forward Voltage	$V_{GS(FWD)}$	I <sub>G</sub> = 500 mA, T <sub>j</sub> = 175 °C		3.1		V	
DC Current Gain	ρ	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 50 A, T <sub>i</sub> = 25 °C		TBD			
DC Current Gain	β	$V_{DS} = 5 \text{ V}, \text{ I}_{D} = 50 \text{ A}, \text{ T}_{j} = 175 ^{\circ}\text{C}$		TBD			
Off Characteristics							
		V <sub>R</sub> = 1200 V, V <sub>GS</sub> = 0 V, T <sub>j</sub> = 25 °C		18			
Drain Leakage Current	I <sub>DSS</sub>	V <sub>R</sub> = 1200 V, V <sub>GS</sub> = 0 V, T <sub>j</sub> = 125 °C		26		μA	
-		$V_R$ = 1200 V, $V_{GS}$ = 0 V, $T_j$ = 175 °C		35		-	
Gate Leakage Current	I <sub>SG</sub>	V <sub>SG</sub> = 20 V, T <sub>i</sub> = 25 °C		20		nA	



### GA50JT12-247

### Electrical Characteristics at T<sub>j</sub> = 175 °C, unless otherwise specified

Parameter	Symbol	Symbol Conditions		Values		Unit
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Capacitance Characteristics						
Gate-Source Capacitance	C <sub>gs</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz		tbd		pF
Input Capacitance	C <sub>iss</sub>	$V_{GS}$ = 0 V, $V_{D}$ = 1 V, f = 1 MHz		tbd		pF
Reverse Transfer/Output Capacitance	$C_{rss}/C_{oss}$	V <sub>D</sub> = 1 V, f = 1 MHz		tbd		pF
Switching Characteristics						
Turn On Delay Time	t <sub>d(on)</sub>			tbd		ns
Rise Time	tr	$V_{DD} = 800 \text{ V}, \text{ I}_{D} = 50 \text{ A},$		tbd		ns
Turn Off Delay Time	t <sub>d(off)</sub>	$R_{G(on)} = R_{G(off)} = 44 \Omega,$ V <sub>GS</sub> = -8/15 V, L = 1.1 mH,		tbd		ns
Fall Time	t <sub>f</sub>	FWD = GB50SLT12.		tbd		ns
Turn-On Energy Per Pulse	Eon	T <sub>j</sub> = 25 °C Refer to Figure 15 for gate current waveform		tbd		μJ
Turn-Off Energy Per Pulse	E <sub>off</sub>			tbd		μJ
Total Switching Energy	E <sub>ts</sub>			tbd		μJ
Turn On Delay Time	t <sub>d(on)</sub>			tbd		
Rise Time	tr	$V_{DD} = 800 \text{ V}, \text{ I}_{D} = 50 \text{ A},$		tbd		ns
Turn Off Delay Time	t <sub>d(off)</sub>	$\begin{array}{c c} R_{G(on)} = R_{G(off)} = 44 \ \Omega, \\ V_{GS} = -8/15 \ V, L = 1.1 \ mH, \\ FWD = GB50SLT12, \\ T_{j} = 175 \ ^{\circ}C \\ \end{array}$ Refer to Figure 15 for gate current		tbd		ns
Fall Time	t <sub>f</sub>			tbd		ns
Turn-On Energy Per Pulse	Eon			tbd		μJ
Turn-Off Energy Per Pulse	E <sub>off</sub>			tbd		μJ
Total Switching Energy	E <sub>ts</sub>	waveform		tbd		μJ

Thermal resistance, junction - case	R <sub>thJC</sub>	0.26	°C/W
monnal recletance, junction cace	· (II)C	0.20	0.11

Figures

TBD



Figure 1: Typical Output Characteristics at 25 °C

Figure 2: Typical Output Characteristics at 125 °C





Figure 3: Typical Output Characteristics at 175 °C

Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

**TBD** 



Figure 5: Normalized On-Resistance and Current Gain vs. Temperature



Figure 6: Typical Blocking Characteristics

TBD



**Figure 7: Capacitance Characteristics** 

Figure 8: Capacitance Characteristics





Figure 9: Typical Hard-switched Turn On Waveforms

Figure 10: Typical Hard-switched Turn Off Waveforms

**TBD** 



Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature



Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

TBD



Figure 13: Typical Turn On Energy Losses vs. Drain Current Figure 14: Typical Turn Off Energy Losses vs. Drain Current







Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency <sup>1</sup>

**TBD** 





Figure 17: Power Derating Curve

Figure 18: Forward Bias Safe Operating Area

TBD

TBD

Figure 19: Turn-Off Safe Operating Area

Figure 20: Transient Thermal Impedance

<sup>1</sup> – Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.

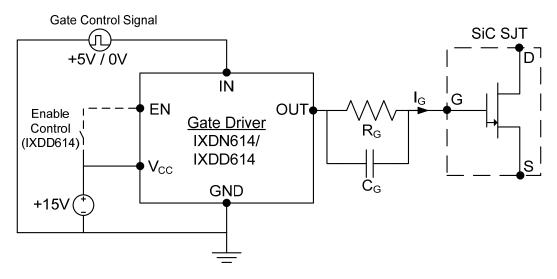


### Gate Drive Technique (Option #1)

To drive the GA50JT12-247 with the lowest gate drive losses, please refer to the dual voltage source gate drive configuration described in Application Note AN-10B (http://www.genesicsemi.com/index.php/references/notes).

### Gate Drive Technique (Option #2)

The GA50JT12-247 can be effectively driven using the IXYS IXDN614 / IXDD614 non-inverting gate driver IC or a comparable product. A typical gate driver configuration along with component values using this driver is offered below. Additional information is available in GeneSiC Application Note AN-10A and from the manufacturer at www.ixys.com.



#### Figure 21: Recommended Gate Diver Configuration (Option #2)

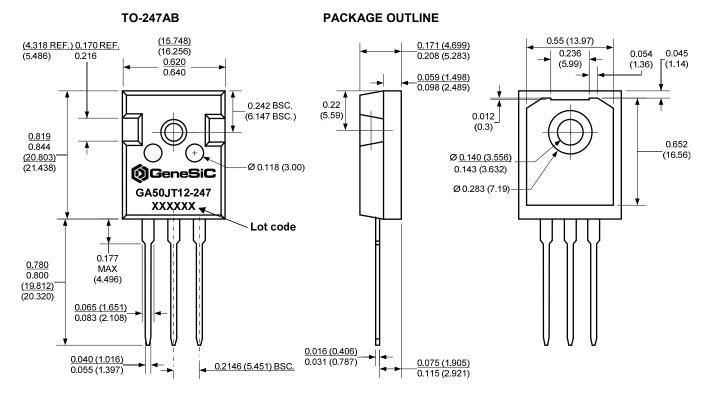
Parameter	Symbol Condit	O and diffience	Values			11
		Conditions	min.	typ.	max.	Unit
Option #2 Gate Drive Conditions (I)	(DD614/IXDN614)					
Supply Voltage	V <sub>cc</sub>		-0.3	15	40	V
Gate Control Input Signal, Low	IN		-5.0	0	0.8	V
Gate Control Input Signal, High	IN		3.0	5.0	V <sub>cc</sub> +0.3	V
Enable, Low	EN	IXDD614 Only			1/3*V <sub>cc</sub>	V
Enable, High	EN	IXDD614 Only	2/3*V <sub>CC</sub>			V
Output Voltage, Low	V <sub>OUT</sub>				0.025	V
Output Voltage, High	Vout		V <sub>CC</sub> -0.025			V
Output Current, Peak	I <sub>OUT</sub>	Package Limited		tbd	14	Α
Output Current, Continuous	I <sub>OUT</sub>			tbd	4.0	А

Gate Resistance	R <sub>G</sub>	I <sub>G</sub> ≈ 0.5 A	5	tbd	Ω
Gate Capacitance	C <sub>G</sub>	I <sub>G</sub> ≈ 0.5 A		tbd	nF



### GA50JT12-247

#### Package Dimensions:



#### NOTE

1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.

2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History					
Date	Revision	Comments	Supersedes		
2013/09/12	0	Initial release			

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### **SPICE Model Parameters**

Copy the following code into a SPICE software program for simulation of the GA50JT12 SJT device.

```
*
     MODEL OF GeneSiC Semiconductor Inc.
*
*
     $Revision: 1.0
                                $
*
     $Date: 26-AUG-2013
                                $
*
*
    GeneSiC Semiconductor Inc.
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    http://www.genesicsemi.com/index.php/sic-products/sjt
*
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* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
.model GA50JT12 NPN
+ IS
          5.00E-47
+ ISE
         1.26E-28
+ EG
          3.2
          100
+ BF
+ BR
         0.55
+ IKF
         3500
+ NF
         1
+ NE
         2
         0.26
+ RB
+ RE
         0.01
+ RC
         0.011
        1.75E-9
+ CJC
+ VJC
         3
+ MJC
         0.5
+ CJE
          5.57E-9
+ VJE
          3
         0.5
+ MJE
          3
+ XTI
+ XTB
          -1.2
+ TRC1
         7.00E-3
+ VCEO
          1200
+ ICRATING 50
+ MFG GeneSiC_Semiconductor
*
* End of GA50JT12 SPICE Model
```